

**Search Notes**

Application/Control No.

10/628,228

Examiner

ALEX LIEW

Applicant(s)/Patent under  
Reexamination

TAKENAKA, HIDEKI

Art Unit

2624

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference		6/5/2008	AL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
382/115,116,118 limited to text search	6/5/2008	AL
Inventor and assignee name search	6/5/2008	AL